



FIG.1

	aging process					reliability test for 1000 hr				
	120Hz		100KHz	leakage	yield	120Hz		100KHz	leakage	yield
	Capacitan e (μ F)	ESR (m Ω)	ESR (m Ω)	current (μ A)	(%)	Capacitan ce (μ F)	ESR (m Ω)	ESR (m Ω)	current (μ A)	(%)
embodiment 1	343	98	8	204.0	100	344	99	7	2.96	100
	348	102	7	124.2		348	106	7	28.4	
	351	105	8	83.8		354	106	7	8.48	
	350	102	7	18.6		350	108	7	3.12	
	349	111	7	51.0		342	111	7	4.82	
embodiment 2	<u>349</u>	<u>119</u>	<u>7</u>	<u>296</u>	80	-	-	-	-	50
	353	103	8	32.9		346	105	8	3.32	
	353	107	8	57.3		354	106	8	4.08	
	357	103	8	37.3		<u>6.7</u>	<u>27130</u>	<u>7680</u>	<u>>20000</u>	
	350	121	8	230		<u>345</u>	<u>122</u>	<u>7</u>	<u>481</u>	

FIG. 2